AO9926B

20V Dual N-Channel MOSFET

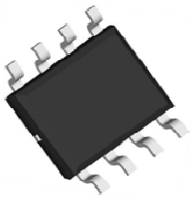
General Description

The AO9926B uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V while retaining a12V $V_{GS(MAX)}$ rating. This device is suitable for use as a uni-directional or bi-directional load switch.

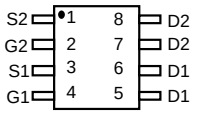
Features

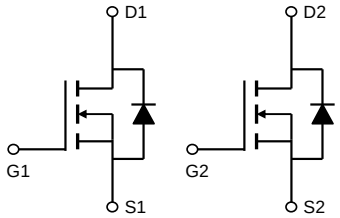
V_{DS}	20V
I_D (at V_{GS}=10V)	7.6A
$R_{DS(ON)}$ (at V_{GS}=10V)	< 23mΩ
$R_{DS(ON)}$ (at V_{GS} =4.5V)	< 26mΩ
$R_{DS(ON)}$ (at V_{GS}=2.5V)	< 34mΩ
$R_{DS(ON)}$ (at V_{GS}=1.8V)	< 52mΩ

SOIC-8



Top View





Absolute Maximum Ratings T_A=25℃ unless otherwise noted				
Parameter		**Symbol**	**Maximum**	**Units**
Drain-Source Voltage		V_{DS}	20	V
Gate-Source Voltage		V_{GS}	±12	V
Continuous Drain Current	T_A=25℃	I_D	7.6	A
	T_A=70℃		6.1	
Pulsed Drain Current [C]		I_{DM}	38	
Power Dissipation [B]	T_A=25℃	P_D	2	W
	T_A=70℃		1.28	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	℃

Thermal Characteristics					
Parameter		**Symbol**	**Typ**	**Max**	**Units**
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	48	62.5	℃/W
Maximum Junction-to-Ambient [A D]	Steady-State		74	90	℃/W
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	32	40	℃/W

Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	20			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=20V, V_{GS}=0V			1	µA
		T_J=55℃			5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±12V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	0.4	0.75	1.1	V
$I_{D(ON)}$	On state drain current	V_{GS}=10V, V_{DS}=5V	38			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=7.6A		16.5	23	mΩ
		T_J=125℃		25	30	
		V_{GS}=4.5V, I_D=7A		18.5	26	mΩ
		V_{GS}=2.5V, I_D=6A		24	34	mΩ
		V_{GS}=1.8V, I_D=2A		32	52	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=7.6A		25		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				2.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz	420	525	630	pF
C_{oss}	Output Capacitance		65	95	125	pF
C_{rss}	Reverse Transfer Capacitance		45	75	105	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	0.8	1.7	2.6	Ω
SWITCHING PARAMETERS						
Q_g(10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=15V, I_D=7.6A		12.5		nC
Q_g(4.5V)	Total Gate Charge			6		nC
Q_{gs}	Gate Source Charge			1		nC
Q_{gd}	Gate Drain Charge			2		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=1.3Ω, R_{GEN}=3Ω		3		ns
t_r	Turn-On Rise Time			7.5		ns
$t_{D(off)}$	Turn-Off DelayTime			20		ns
t_f	Turn-Off Fall Time			6		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=7.6A, dI/dt=100A/µs		14		ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=7.6A, dI/dt=100A/µs		6		nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with T_A =25℃. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}$=150℃, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=150℃. Ratings are based on low frequency and duty cycles to keep initialT_J=25℃.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(MAX)}$=150℃. The SOA curve provides a single pulse ratin g.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

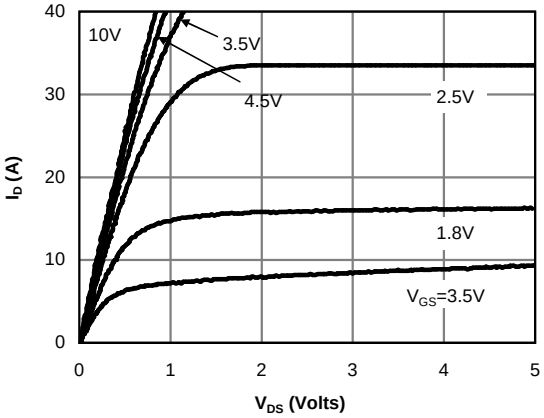


Fig 1: On-Region Characteristics (Note E)

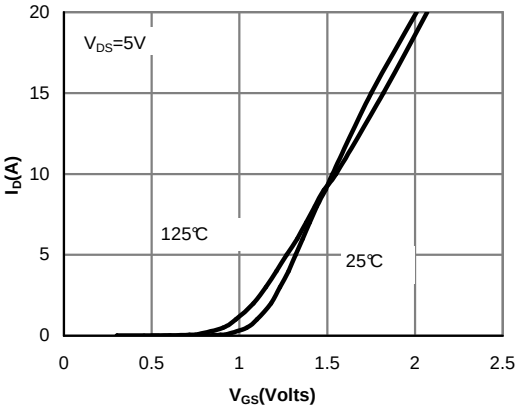


Figure 2: Transfer Characteristics (Note E)

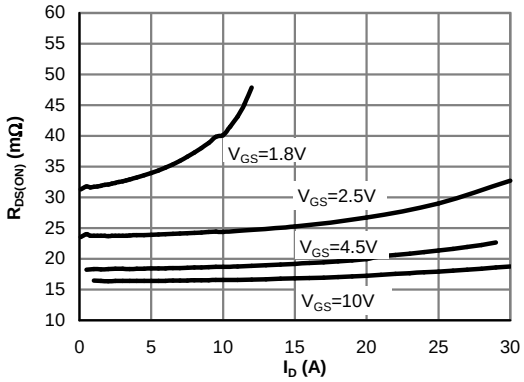


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

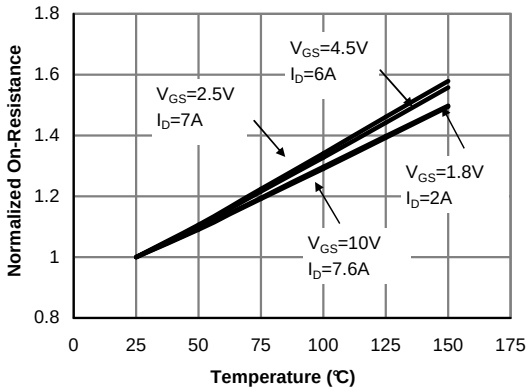


Figure 4: On-Resistance vs. Junction Temperature (Note E)

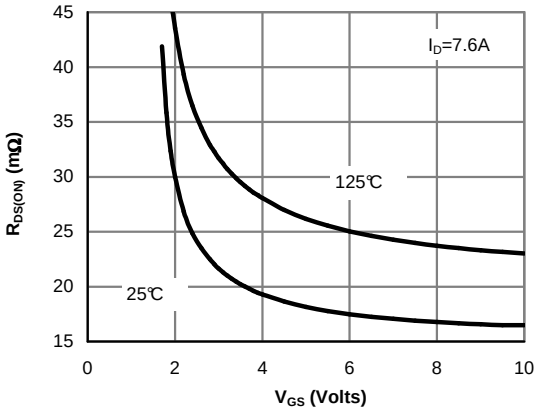


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

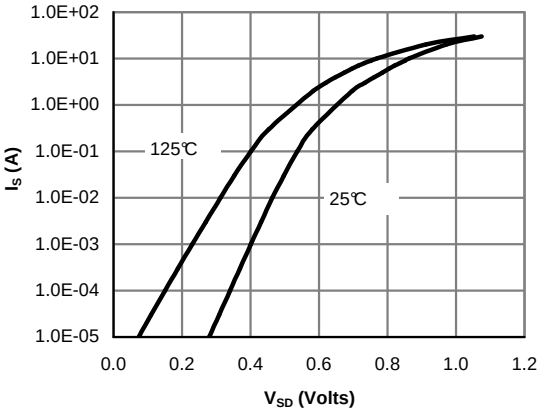


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

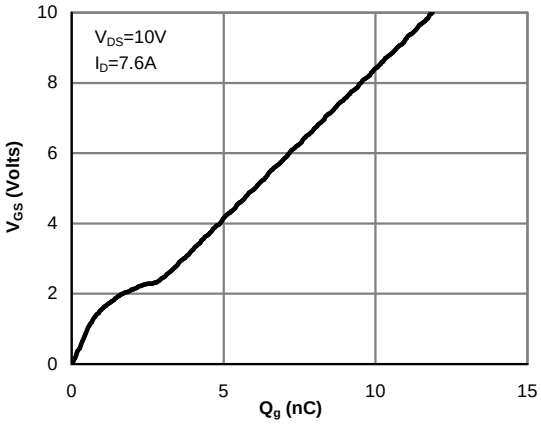


Figure 7: Gate-Charge Characteristics

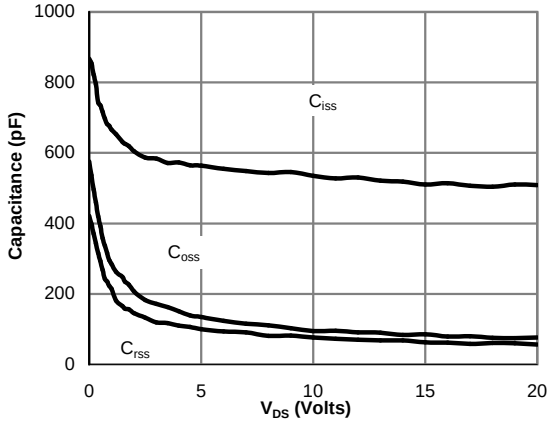


Figure 8: Capacitance Characteristics

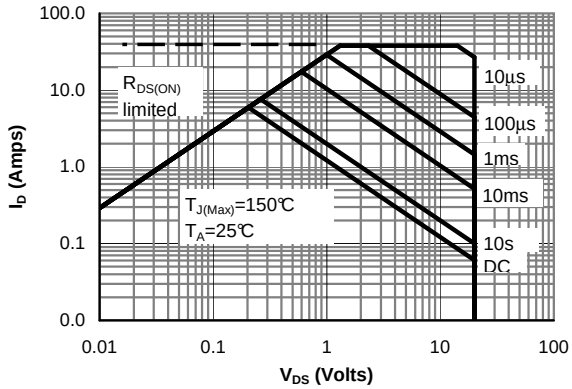


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

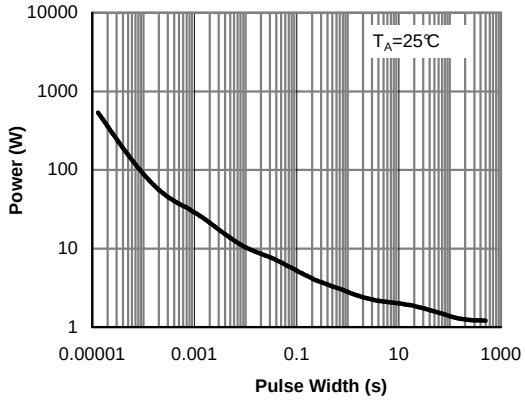


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

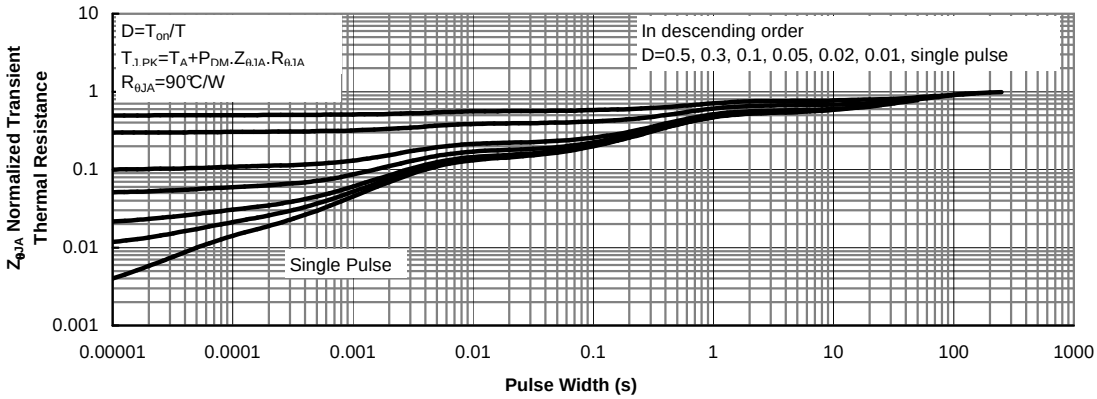
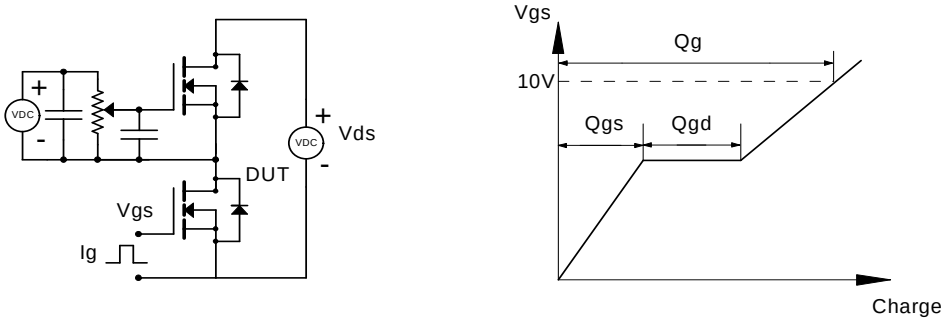
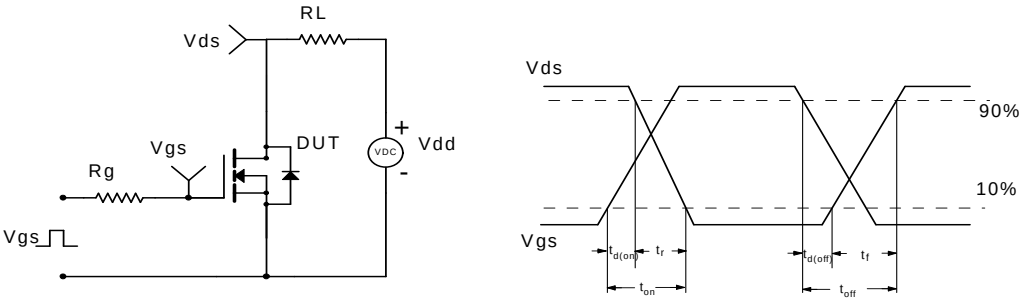


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms